

<b>Notice of References Cited</b>	Application/Control No. 09/613,292	Applicant(s)/Patent Under Reexamination CHECK, LA-TEE	
	Examiner Thu V Huynh	Art Unit 2178	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,317,131	11-2001	Basso et al.	345/474
	B	US-6,092,107	07-2000	Eleftheriadis et al.	709/217
	C	US-6,654,931	11-2003	Haskell et al.	715/500.1
	D	US-6,631,403	10-2003	Deutsch et al.	709/217
	E	US-6,665,318	12-2003	Tomokane et al.	370/535
	F	US-6,463,444	10-2002	Jain et al.	707/104.1
	G	US-6,697,869	02-2004	Mallart et al.	709/231
	H	US-6,496,233	12-2002	Christine et al.	375/240.02
	I	US-6,185,602	02-2001	Bayrakeri, Sadik	709/204
	J	US-6,611,262	08-2003	Suzuki, Teruhiko	345/419
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.